

Application/Control No.	Applicant(s)/Patent under Reexamination
10/802,628	SATOH, TOMIO
Examiner	Art Unit
Joseph Chang	2817

SEARCHED					
Class	Subclass	Date	Examiner		
331	116R, 117R	6/17/2005	JC		
			<u></u>		
			·		
•					

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
	1				
		·			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		